

Application/Control No.	Applicant(s)/Patent under Reexamination
10/792,262	TSCHANZ ET AL.
Examiner	Art Unit
Jeffrey S. Zweizig	2816

SEARCHED									
Class	Subclass	Date	Examiner						
327	512	2/16/2005	JZ						
	513								
	530								
	534								
	535								
	537								
	540								
V	543	<i>\\</i>	$\forall$						
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INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				
327	513	2/23/2005	JZ				
V	534	<b>V</b>	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
	,		DATE	EXMR		
EAST			2/16/2005	JZ		
L #	Hits		Search	Text		
L2	489961	substrat	e			
L3	974105	body				
L4	3277	back adj	gate			
L5	649	backgate	:			
L6	133522 8	2 or 3 c	or 4 or	5		
L7	136270	6 and bi	.as			
L8	146073 9	off or l	eak or	leakag		
 L9	41941	8 adj cu	rrent			
L10	8975	7 and 9				
L11	124747 9	temperature		/		
L12	5081					
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